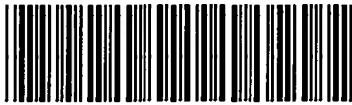


Search Notes

Application/Control No.

10/649,625

Examiner

Jim Vannucci

Applicant(s)/Patent under
Reexamination

SEKI, YUICHI

Art Unit

2828

SEARCHED

| Class | Subclass | Date | Examiner |
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| same as above | | 2/21/2006 | JV |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| 372/43, 372/50, identical, wafer lot | 2/21/2006 | JV |
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